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/J.R./	AO	2003-246268	09/02/03	JP (with English abstract)				NO
/J.R./	AP	10-304346	11/13/98	JP (with English abstract)		<u></u>		NO
/J.R./	AQ	09-097337	04/08/97	JP (with English abstract)				NO
/J.R./	AR	2001-143184	05/25/01	JP (with English abstract)		<u> </u>		NO
/J.R./	AS	2001-134761	05/18/01	JP (with English abstract)				NO
/J.R./	AT	7-73388	03/17/95	JP (equivalent of US 6167143)				NO
/J.R./	AU	10-341427	12/22/98	JP (with English abstract)				NO
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/J.R./	AP	2000-184359	06/30/2000	Japan (with English Abstract)				×
/J.R./	AQ	9-93565	04/04/1997	Japan (with English Abstract)				×
/J.R./	AR	9-193803	07/29/1997	Japan (with English Abstract)				×
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